

Supporting Information

Characterisation of Charge Conduction Networks in Poly(3-hexylthiophene)/Polystyrene Blends using Noise Spectroscopy

Aled T. Williams,^a Paul Farrar^a, Andrew J. Gallant^a, Del Atkinson^b and Chris Groves^{*a}

^a School of Engineering and Computing Sciences, Durham University, Durham, DH1 3LE, UK.

^b Department of Physics, Durham University, Durham, DH1 3LE, UK.

E-mail: chris.groves@durham.ac.uk

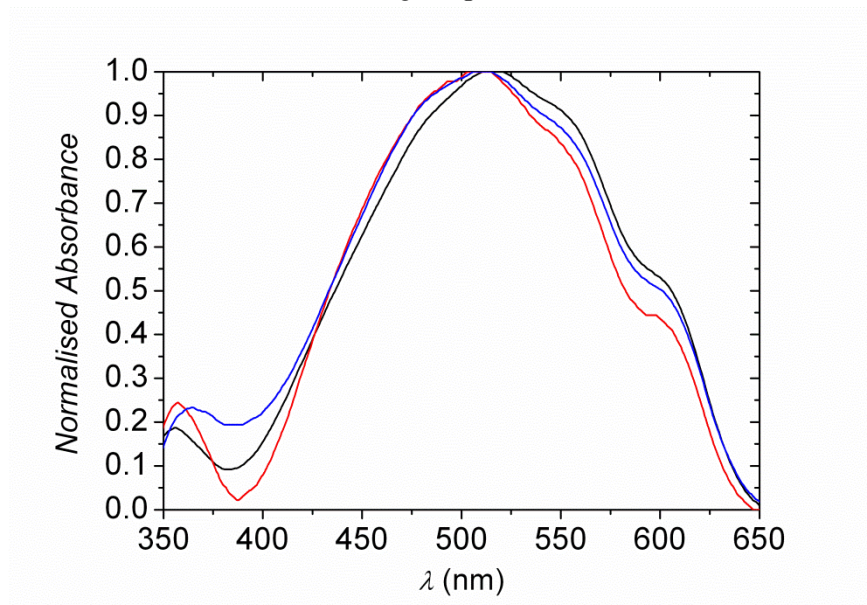


Fig. S1 UV-visible spectrum for films of pristine P3HT ($p = 1$) (black), $p = 0.41$ *i*-PS (blue) $p = 0.37$ *a*-PS (red). Spectra normalised to λ_{max} .

Table S1 Summary of film thickness values from AFM measurements.

Device	Total Film Thickness (nm)	Blend Thickness (nm) [a]	RMS Roughness (nm)
$p = 1$ (P3HT)	86	40	1.62
$p = 0.79$ <i>a</i> -PS	79	33	3.72
$p = 0.37$ <i>a</i> -PS	86	40	1.22
$p = 0.80$ <i>i</i> -PS	85	39	8.83
$p = 0.41$ <i>i</i> -PS [b]	64 and 93	18 and 47	11.30
$p = 0.31$ <i>i</i> -PS	89	43	7.99
$p = 0.21$ <i>i</i> -PS	87	41	1.74
$p = 0.12$ <i>i</i> -PS	77	31	1.37

[a] Calculated by subtracting the thickness of the PEDOT:PSS layer; consistently measured as 46 nm.

[b] The $p = 0.41$ *i*-PS blend shows deep web like features resulting in two values of total film thickness.